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# JEITA Guideline Compatible Stand-Alone Synchronous Switch-Mode Li-Ion or Li-Polymer Battery Charger With System Power Selector and Low I<sub>a</sub>

Check for Samples: bq24616

### FEATURES

- Battery Thermistor Sense for JEITA Guideline Compatible Charger
- 600-kHz NMOS-NMOS Synchronous Buck Converter
- Stand-Alone Charger Support for Li-lon or Li-Polymer
- 5-V–28-V VCC Input Operating Range and Supports 1-6 Battery Cells
- Up to 10A Charge Current and Adapter Current
- High-Accuracy Voltage and Current Regulation
  - ±0.5% Charge Voltage Accuracy
  - ±3% Charge Current Accuracy
  - ±3% Adapter Current Accuracy
- Integration
  - Automatic System Power Selection From Adapter or Battery
  - Internal Loop Compensation
  - Internal Soft Start
  - Dynamic Power Management
- Safety Protection
  - Input Overvoltage Protection
  - Battery Detection
  - Reverse Protection Input FET
  - Programmable Safety Timer
  - Charge Overcurrent Protection
  - Battery Short Protection
  - Battery Overvoltage Protection
  - Thermal Shutdown
- Status Outputs
  - Adapter Present
  - Charger Operation Status
- Charge Enable Pin
- 6-V Gate Drive for Synchronous Buck Converter
- 30-ns Driver Dead-Time and 99.5% Max Effective Duty Cycle
- 24-pin, 4-mm × 4-mm QFN Package
- Energy Star Low Quiescent Current Iq

- < 15-µA Off-State Battery Discharge Current</p>
- < 1.5-mA Off-State Input Quiescent Current

### APPLICATIONS

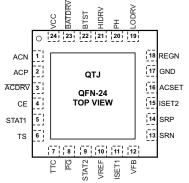
- Netbook, Mobile Internet Device and Ultra-Mobile PC
- Industrial and Medical Equipment
- Personal Digital Assistants
- Handheld Terminals
- Portable Equipment

### DESCRIPTION

The bq24616 is a highly integrated, Japan Electronic Information Technology Association (JEITA) auideline-compatible. Li-polymer Li-ion or switch-mode battery charge controller. It offers a constant-frequency synchronous switching PWM controller with high-accuracy charge-current and -voltage regulation, charge preconditioning, termination, adapter current regulation. and charge-status monitoring.

The bq24616 charges the battery in three phases: preconditioning, constant-current, and constant-voltage. Charge is terminated when the current reaches a minimum user-selectable level. A programmable charge timer provides a safety backup. The bq24616 automatically restarts the charge cycle if the battery voltage falls below an internal threshold, and enters a low-quiescent-current sleep mode when the input voltage falls below the battery voltage.

#### PACKAGE AND PIN-OUT



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





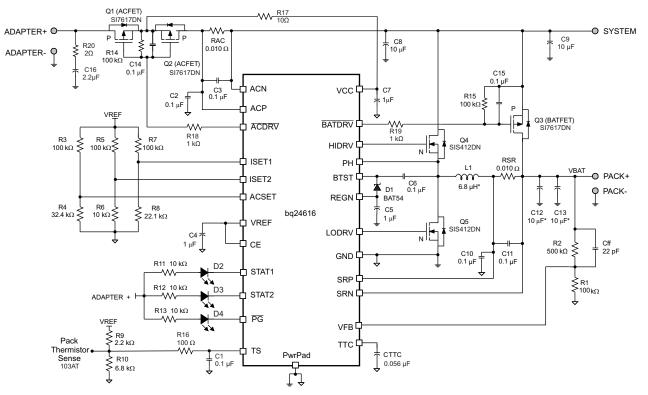
This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### **DESCRIPTION (CONTINUED)**

The bq24616 controls external switches to prevent battery discharge back to the input and to connect the battery to the system using 6-V gate drives for system efficiency. The bq24616 features dynamic power management (DPM). The DPM reduces battery charge current when the input power limit is reached to avoid overloading the ac adapter while supplying the load and the battery charger simultaneously. A highly accurate current-sense amplifier enables precise measurement of input current from the ac adapter to monitor the overall system power.

### TYPICAL APPLICATION



VIN = 19 V; 3-cell; I<sub>adapter\_limit</sub> = 4 A; I<sub>pre-charge</sub> = I<sub>term</sub> = 0.3 A; 5-hour safety timer; I<sub>charge</sub> = 1.5 A (0–10°C), 3 A (10°C–60°C); V<sub>BAT</sub> = 12.6 V (0°C–45°C), 12.3 V (45°C–50°C), 12.15 V (50°C–60°C).

#### **ORDERING INFORMATION**

PART NUMBER	IC MARKING	PACKAGE	ORDERING NUMBER (Tape and Reel)	QUANTITY		
h=04040					bq24616RGER	3000
bq24616	QTJ	24-pin 4-mm × 4-mm QFN	bq24616RGET	250		



#### THERMAL INFORMATION

		bq24616	
	THERMAL METRIC <sup>(1)</sup>	RGE	UNIT
		24 PINS	
θ <sub>JA</sub>	Junction-to-ambient thermal resistance <sup>(2)</sup>	43	°C/W
θ <sub>JCtop</sub>	Junction-to-case (top) thermal resistance <sup>(3)</sup>	54.3	°C/W
$\theta_{JB}$	Junction-to-board thermal resistance <sup>(4)</sup>	20	°C/W
Ψ <sub>JT</sub>	Junction-to-top characterization parameter <sup>(5)</sup>	0.6	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter <sup>(6)</sup>	19	°C/W
θ <sub>JCbot</sub>	Junction-to-case (bottom) thermal resistance <sup>(7)</sup>	4	°C/W

For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.
 The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as

specified in JESD51-7, in an environment described in JESD51-2a.

(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.

(5) The junction-to-top characterization parameter,  $\psi_{JT}$ , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining  $\theta_{JA}$ , using a procedure described in JESD51-2a (sections 6 and 7).

(6) The junction-to-board characterization parameter,  $\psi_{JB}$ , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining  $\theta_{JA}$ , using a procedure described in JESD51-2a (sections 6 and 7).

(7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

### **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted) (1) (2) (3)

			VAI	VALUE	
			MIN	MAX	
	Voltage range	VCC, AC <u>P,</u> ACN, SRP, SRN, BATDRV, ACDRV, CE, STAT1, STAT2, PG	-0.3	33	V
		РН	-2	36	V
		VFB	-0.3	16	V
		REGN, LODRV, ACSET, TS, TTC	-0.3	7	V
		BTST, HIDRV with respect to GND	-0.3	39	V
		VREF, ISET1, ISET2	-0.3	3.6	V
	Maximum difference voltage	ACP-ACN, SRP-SRN	-0.5	0.5	V
TJ	Junction temperature rai	nge	-40	155	°C
T <sub>stg</sub>	Storage temperature range		-55	155	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to GND if not specified. Currents are positive into, negative out of the specified terminal. Consult the Packaging section of the data sheet for thermal limitations and considerations of packages.

(3) Must have a series resistor between battery pack and VFB if battery-pack voltage is expected to be greater than 16 V. Usually the resistor-divider top resistor takes care of this.

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### **RECOMMENDED OPERATING CONDITIONS**

			VAI	VALUE	
			MIN	MAX	
		VCC, AC <u>P,</u> ACN, SRP, SRN, BATDRV, ACDRV, CE, STAT1, STAT2, PG	-0.3	28	V
		PH	-2	30	V
		VFB	-0.3	14	V
	Voltage range	REGN, LODRV, ACSET, TS, TTC	-0.3	6.5	V
		BTST, HIDRV with respect to GND	-0.3	34	V
		ISET1, ISET2	-0.3	3.3	V
		VREF	0	3.3	V
	Maximum difference voltage	ACP-ACN, SRP-SRN	-0.2	0.2	V
TJ	Junction temperature rai	nge	0	125	°C
T <sub>stg</sub>	Storage temperature rar	Storage temperature range		155	°C



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# ELECTRICAL CHARACTERISTICS

 $5 \text{ V} \le \text{V}_{\text{VCC}} \le 28 \text{ V}, 0^{\circ}\text{C} < \text{T}_{\text{J}} < 125^{\circ}\text{C}$ , typical values are at  $\text{T}_{\text{A}} = 25^{\circ}\text{C}$ , with respect to GND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OPERATING (	CONDITIONS					
V <sub>VCC_OP</sub>	VCC input voltage operating range		5		28	V
QUIESCENT C	CURRENTS		1		1	
	Total battery discharge current (sum of currents into VCC, BTST, PH, ACP, ACN, SRP, SRN, VFB), $V_{FB} \le V_{FB_{-}REG}$	V <sub>VCC</sub> < V <sub>SRN</sub> , V <sub>VCC</sub> > V <sub>UVLO</sub> (SLEEP)			15	μA
IBAT	Battery discharge current (sum of	$V_{VCC}$ > $V_{SRN}$ , $V_{VCC}$ > $V_{UVLO}$ CE = LOW			5	μA
	currents into BTST, PH, SRP, SRN, VFB), $V_{FB} \leq V_{FB_{REG}}$	$V_{VCC}$ > $V_{SRN},$ $V_{VCC}$ > $V_{VCCLOW}$ CE = HIGH, charge done			5	μA
		$V_{VCC}$ > $V_{SRN}$ , $V_{VCC}$ > $V_{UVLO}$ CE = LOW (IC quiescent current)		1	1.5	
I <sub>AC</sub>	Adapter supply current (current into VCC,ACP,ACN pin)	$V_{VCC}$ > $V_{SRN}$ , $V_{VCC}$ > $V_{VCCLOW}$ , CE = HIGH, charge done		2	5	mA
		$V_{VCC} > V_{SRN}$ , $V_{VCC} > V_{VCCLOW}$ , CE = HIGH, charging, Qg_total = 20 nC		25		
CHARGE VOL	TAGE REGULATION					
		$V_{T3} < V_{TS} < V_{T1}$		2.1		
V <sub>FB_REG</sub>	Feedback regulation voltage	$V_{T4} < V_{TS} < V_{T3}$		2.05		V
		$V_{T5} < V_{TS} < V_{T4}$		2.025		
		$T_J = 0$ to $85^{\circ}C$	-0.5%		-0.5%	
	Charge voltage regulation accuracy	$T_{\rm J} = -40$ to $125^{\circ}$ C	-0.7%		-0.7%	
I <sub>VFB</sub>	Leakage current into V <sub>FB</sub> pin	V <sub>FB</sub> = 2.1 V, 2.05 V, 2.025 V			100	nA
CURRENT RE	GULATION – FAST CHARGE				·	
V <sub>ISET1</sub>	ISET1 voltage range				2	V
V <sub>IREG_CHG</sub>	SRP-SRN current-sense voltage range	$V_{IREG_{CHG}} = V_{SRP} - V_{SRN}$			100	mV
K <sub>ISET1</sub>	Charge-current set factor (amps of charge current per volt on ISET1 pin)	$R_{SENSE} = 10 \text{ m}\Omega$		5		A/V
		$V_{IREG_CHG} = 40 \text{ mV}$	-3%		3%	
		V <sub>IREG_CHG</sub> = 20 mV	-4%		4%	
	Charge current-regulation accuracy	V <sub>IREG_CHG</sub> = 5 mV	-25%		25%	
		$V_{IREG_{CHG}} = 1.5 \text{ mV} (V_{SRN} > 3.1 \text{ V})$	-40%		40%	
I <sub>ISET1</sub>	Leakage current into ISET1 pin	V <sub>ISET1</sub> = 2 V			100	nA
CURRENT RE	GULATION – PRECHARGE					
V <sub>ISET2</sub>	ISET2 voltage range				2	V
K <sub>ISET2</sub>	Precharge current-set factor (amps of precharge current per volt on ISET2 pin)	$R_{SENSE} = 10 \text{ m}\Omega$		1		A/V
		V <sub>IREG_PRECH</sub> = 20 mV	-4%		4%	
	Precharge current-regulation accuracy	V <sub>IREG_PRECH</sub> = 5 mV	-25%		25%	
		$V_{IREG_{PRECH}} = 1.5 \text{ mV} (V_{SRN} < 3.1 \text{ V})$	-55%		55%	
I <sub>ISET2</sub>	Leakage current into ISET2 pin	V <sub>ISET2</sub> = 2V			100	nA

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### **ELECTRICAL CHARACTERISTICS (continued)**

 $5 \text{ V} \le \text{V}_{\text{VCC}} \le 28 \text{ V}, 0^{\circ}\text{C} < \text{T}_{\text{J}} < 125^{\circ}\text{C}$ , typical values are at  $\text{T}_{\text{A}} = 25^{\circ}\text{C}$ , with respect to GND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
CHARGE TERM	INATION					
K <sub>TERM</sub>	Termination current-set factor (amps of termination current per volt on ISET2 pin)	R <sub>SENSE</sub> = 10 mΩ		1		A/V
		V <sub>ITERM</sub> = 20 mV	-4%		4%	
	Termination-current accuracy	V <sub>ITERM</sub> = 5 mV	-25%		25%	
		V <sub>ITERM</sub> = 1.5 mV	-45%		45%	
	Deglitch time for termination (both edge)			100		ms
t <sub>QUAL</sub>	Termination qualification time	$V_{BAT}$ > $V_{RECH}$ and $I_{CHG}$ < $I_{TERM}$		250		ms
	Termination qualification current	Discharge current once termination is detected		2		mA
NPUT CURREN	IT REGULATION					
V <sub>ACSET</sub>	ACSET voltage range				2	V
V <sub>IREG_DPM</sub>	ACP-ACN current sense voltage range	$V_{IREG_{DPM}} = V_{ACP} - V_{ACN}$			100	mV
K <sub>ACSET</sub>	Input current set factor (amps of input current per volt on ACSET pin)	$R_{SENSE} = 10 \text{ m}\Omega$		5		A/V
		V <sub>IREG_DPM</sub> = 40 mV	-3%		3%	
ACSET	Input current regulation accuracy leakage current in to ACSET pin	V <sub>IREG_DPM</sub> = 20 mV	-4%		4%	
		V <sub>IREG_DPM</sub> = 5 mV	-25%		25%	
ISET1	Leakage current in to ACSET pin	V <sub>ACSET</sub> = 2 V			100	nA
NPUT UNDERV	OLTAGE LOCKOUT COMPARATOR (UVLC	))			1	-
V <sub>UVLO</sub>	AC undervoltage rising threshold	Measure on VCC	3.65	3.85	4	V
V <sub>UVLO_HYS</sub>	AC undervoltage hysteresis, falling			350		mV
	Falling threshold, disable charge	Measure on VCC		4.1		V
	Rising threshold, resume charge			4.35	4.5	V
SLEEP COMPA	RATOR (REVERSE DISCHARGING PROTE					
V <sub>SLEEP</sub> _FALL	SLEEP falling threshold	V <sub>VCC</sub> – V <sub>SRN</sub> to enter SLEEP	40	100	150	mV
V <sub>SLEEP_HYS</sub>	SLEEP hysteresis			500		mV
SLEEP_HTS	SLEEP rising delay	VCC falling below SRN, Delay to turn off ACFET		1		μs
	SLEEP falling delay	VCC rising above SRN, Delay to turn on ACFET		30		ms
	SLEEP rising shutdown deglitch	VCC falling below SRN, Delay to enter SLEEP mode		100		ms
	SLEEP falling powerup deglitch	VCC rising above SRN, Delay to exit SLEEP mode		30		ms
ACN / SRN CON	0 0	Vee haing above only, being to exit offer inde		50		1113
	ACN to SRN falling threshold	V <sub>ACN</sub> – V <sub>SRN</sub> to turn on BATFET	100	200	310	mV
V <sub>ACN-SRN_FALL</sub>		VACN – VSRN to turn on BATT ET	100		310	
V <sub>ACN-SRN_HYS</sub>	ACN to SRN rising hysteresis	W W SW		100 2		mV
	ACN to SRN rising deglitch	$V_{ACN} - V_{SRN} > V_{ACN-SRN_{RISE}}$				ms
BAT LOWV CON	ACN to SRN falling deglitch	$V_{ACN} - V_{SRN} < V_{ACN-SRN_FALL}$	I	50		μs
DAT LOWV CON	-					
V <sub>LOWV</sub>	Precharge to fastcharge transition (LOWV threshold)	Measured on VFB pin, rising	1.534	1.55	1.566	V
VLOWV_HYS	LOWV hysteresis			100		mV
	LOWV rising deglitch	VFB falling below V <sub>LOWV</sub>		25		ms
	LOWV falling deglitch	VFB rising above $V_{LOWV}$ + $V_{LOWV_HYS}$		25		ms
RECHARGE CO	MPARATOR	1	1			
V <sub>RECHG</sub>	Recharge threshold (with-respect-to $V_{REG}$ )	Measured on VFB pin, Falling	35	50	65	mV
	Recharge rising deglitch	VFB decreasing below V <sub>RECHG</sub>		10	T	ms
	Recharge falling deglitch	VFB decreasing above V <sub>RECHG</sub>		10		ms

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### **ELECTRICAL CHARACTERISTICS (continued)**

### $5 \text{ V} \le \text{V}_{\text{VCC}} \le 28 \text{ V}, 0^{\circ}\text{C} < \text{T}_{\text{J}} < 125^{\circ}\text{C}$ , typical values are at $\text{T}_{\text{A}} = 25^{\circ}\text{C}$ , with respect to GND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BAT OVERVOI	LTAGE COMPARATOR		1			
V <sub>OV_RISE</sub>	Overvoltage rising threshold	As percentage of $V_{FB}$ ,T1 – T5		104%		
V <sub>OV_FALL</sub>	Overvoltage falling threshold	As percentage of V <sub>FB</sub> ,T1 – T5		102%		
	OLTAGE COMPARATOR (ACOV)					
V <sub>ACOV</sub>	AC overvoltage rising threshold on VCC		31.04	32	32.96	V
V <sub>ACOV_HYS</sub>	AC overvoltage falling hysteresis			1		V
	AC overvoltage deglitch (both edges)	Delay to changing the STAT pins		1		ms
	AC overvoltage rising deglitch	Delay to turn-off ACFET, disable charge		1		ms
	AC overvoltage falling deglitch	Delay to turn on ACFET, resume charge		20		ms
THERMAL SHU	UTDOWN COMPARATOR				·	
Т <sub>SHUT</sub>	Thermal shutdown rising temperature	Temperature increasing		145		°C
T <sub>SHUT_HYS</sub>	Thermal shutdown hysteresis			15		°C
	Thermal shutdown rising deglitch	Temperature increasing		100		μs
	Thermal shutdown falling deglitch	Temperature decreasing		10		ms
THERMISTOR	COMPARATOR					
V <sub>T1</sub>	T1 (0 °C) threshold, charge suspended below this temperature	$V_{\text{TS}}$ rising, as percentage of $V_{\text{VREF}}$	70.2%	70.8%	71.4%	
V <sub>T1-HYS</sub>	Charge back to $I_{CHARGE}/2$ and $V_{FB} = 2.1$ V above this temperature.	Hysteresis, V <sub>TS</sub> falling		0.6%		
V <sub>T2</sub>	T2 (10 °C) threshold, charge back to $I_{CHARGE}/2$ and $V_{FB}$ = 2.1 V below this temperature.	$V_{\text{TS}}$ rising, as percentage of $V_{\text{VREF}}$	68.0%	68.6%	69.2%	
V <sub>T2-HYS</sub>	Charge back to $I_{CHARGE}$ and $V_{FB}$ = 2.1 V above this temperature.	Hysteresis, V <sub>TS</sub> falling		0.8%		
V <sub>T3</sub>	T3 (45 °C) threshold, charge back to $I_{CHARGE}$ and $V_{FB}$ = 2.05 V above this temperature.	$V_{\text{TS}}$ falling, as percentage of $V_{\text{VREF}}$	55.5%	56.1%	56.7%	
V <sub>T3-HYS</sub>	Charge back to $I_{CHARGE}$ and $V_{FB}$ = 2.1 V below this temperature.	Hysteresis, V <sub>TS</sub> rising		0.8%		
V <sub>T4</sub>	T4 (50 °C) threshold, charge back to $I_{CHARGE}$ and $V_{FB}$ = 2.025 V above this temperature.	$V_{\text{TS}}$ falling, as percentage of $V_{\text{VREF}}$	53.2%	53.7%	54.2%	
V <sub>T4-HYS</sub>	Charge back to $I_{CHARGE}$ and $V_{FB} = 2.05$ V below this temperature.	Hysteresis, V <sub>TS</sub> rising		0.8%		
V <sub>T5</sub>	T5 (60 °C) threshold, charge suspended above this temperature.	$V_{\text{TS}}$ falling, as percentage of $V_{\text{VREF}}$	47.6%	48.1%	48.6%	
V <sub>T5-HYS</sub>	Charge back to $I_{CHARGE}$ and $V_{FB}$ = 2.025 V below this temperature.	Hysteresis, V <sub>TS</sub> rising		1.2%		
	Deglitch time for temperature out-of-valid-charge-range detection	$V_{TS} < V_{T5}$ or $V_{TS} > V_{T1}$		400		ms
	Deglitch time for temperature in-valid-range detection	$V_{TS}$ > $V_{T5}$ + $V_{T5}_{HYS}$ or $V_{TS}$ < $V_{T1}$ - $V_{T1}_{HYS}$		20		ms
	Deglitch time for temperature detection above/below T2, T3, T4 threshold			25		ms
	Charge current when $V_{TS}$ between $V_{T1}$ and $V_{T2}$ range			I <sub>CHARGE</sub> /2		
CHARGE OVE	RCURRENT COMPARATOR (CYCLE-BY-CYC	CLE)				
	Charge overcurrent falling threshold	Current rising in non-synchronous mode, measure on $V_{(SRP-SRN)},V_{SRP}$ < 2 V		45.5		mV
V <sub>oc</sub>		Current rising, as percentage of V <sub>(IREG_CHG)</sub> , in synchronous mode, V <sub>SRP</sub> > 2.2V		160%		
- 00	Charge overcurrent threshold floor	Minimum OCP threshold in synchronous mode, measure on V <sub>(SRP-SRN)</sub> , V <sub>SRP</sub> > 2.2 V		50		mV
	Charge overcurrent threshold ceiling	Maximum OCP threshold in synchronous mode, measure on V <sub>(SRP-SRN)</sub> , V <sub>SRP</sub> > 2.2 V		180		mV

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### **ELECTRICAL CHARACTERISTICS (continued)**

 $5 \text{ V} \le \text{V}_{\text{VCC}} \le 28 \text{ V}$ , 0°C < T<sub>J</sub> < 125°C, typical values are at T<sub>A</sub> = 25°C, with respect to GND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
CHARGE UNDE	RCURRENT COMPARATOR (CYCLE-BY-C	YCLE)			1	
VISYNSET	Charge undercurrent falling threshold	Switch from SYNCH to NON-SYNCH, $V_{SRP} > 2.2 V$	1	5	9	mV
	RTED COMPARATOR (BATSHORT)					
V <sub>BATSHT</sub>	BAT short falling threshold, forced non-syn mode	V <sub>SRP</sub> falling		2		V
V <sub>BATSHT_HYS</sub>	BAT short rising hysteresis			200		mV
V <sub>BATSHT_DEG</sub>	Deglitch on both edges			1		μs
LOW CHARGE	CURRENT COMPARATOR					
V <sub>LC</sub>	Low charge current (average) falling threshold to force into non-synchronous mode	Measure on $V_{(SRP-SRN)}$		1.25		mV
V <sub>LC_HYS</sub>	Low charge current, rising hysteresis			1.25		mV
$V_{LC_{DEG}}$	Deglitch on both edge			1		μs
VREF REGULA	TOR					
V <sub>VREF_REG</sub>	VREF regulator voltage	V <sub>VCC</sub> > V <sub>UVLO</sub> , (0–35 mA load)	3.267	3.3	3.333	V
I <sub>VREF_LIM</sub>	VREF current limit	$V_{VREF} = 0 V, V_{VCC} > V_{UVLO}$	35			mA
REGN REGULA	TOR	•				
V <sub>REGN_REG</sub>	REGN regulator voltage	V <sub>VCC</sub> > 10 V, CE = HIGH, (0–40 mA load)	5.7	6	6.3	V
I <sub>REGN_LIM</sub>	REGN current limit	V <sub>REGN</sub> = 0 V, V <sub>VCC</sub> > V <sub>UVLO</sub> , CE = HIGH	40			mA
TTC INPUT AND	D SAFETY TIMER					
T <sub>PRECHG</sub>	Precharge safety timer range <sup>(1)</sup>	Precharge time before fault occurs	1440	1800	2160	S
T <sub>CHARGE</sub>	Fast-charge safety-timer range, with ±10% accuracy <sup>(1)</sup>	Tchg = C <sub>TTC</sub> × K <sub>TTC</sub>	1		10	h
	Fast-charge timer accuracy <sup>(1)</sup>	0.01 μF ≤ C <sub>TTC</sub> ≤ 0.11 μF	-10%		10%	
K <sub>TTC</sub>	Timer multiplier			5.6		min/nF
	TTC low threshold	$V_{\text{TTC}}$ below this threshold disables the safety timer and termination			0.4	V
	TTC oscillator high threshold			1.5		V
	TTC oscillator low threshold			1		V
	TTC source/sink current		45	50	55	μA
BATTERY SWIT	CH (BATFET) DRIVER	•				
R <sub>DS_BAT_OFF</sub>	BATFET turnoff resistance	V <sub>ACN</sub> > 5 V			150	Ω
R <sub>DS_BAT_ON</sub>	BATFET turnon resistance	V <sub>ACN</sub> > 5 V			20	kΩ
V <sub>BATDRV_REG</sub>	BATFET drive voltage	$V_{BATDRV\_REG}$ = $V_{ACN}$ – $V_{BATDRV}$ when $V_{ACN}$ > 5 V and BATFET is on	4.2		7	V
AC SWITCH (AC	CFET) DRIVER					
R <sub>DS_AC_OFF</sub>	ACFET turnoff resistance	V <sub>VCC</sub> > 5 V			30	Ω
R <sub>DS_AC_ON</sub>	ACFET turnon resistance	V <sub>VCC</sub> > 5 V			20	kΩ
V <sub>ACDRV_REG</sub>	ACFET drive voltage	$V_{ACDRV\_REG}$ = $V_{VCC}$ – $V_{ACDRV}$ when $V_{VCC}$ > 5 V and ACFET is on	4.2		7	V
AC / BAT MOSE	ET DRIVERS TIMING					
	Driver dead time	Dead time when switching between AC and BAT		10		μs

(1) Verified by design



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### ELECTRICAL CHARACTERISTICS (continued)

### $5 \text{ V} \le \text{V}_{\text{VCC}} \le 28 \text{ V}, 0^{\circ}\text{C} < \text{T}_{\text{J}} < 125^{\circ}\text{C}$ , typical values are at $\text{T}_{\text{A}} = 25^{\circ}\text{C}$ , with respect to GND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BATTERY DETE	CTION	· · · · · · · · · · · · · · · · · · ·				
t <sub>WAKE</sub>	Wake time	Maximum time charge is enabled		500		ms
IWAKE	Wake current	$R_{SENSE} = 10 m\Omega$	50	125	200	mA
t <sub>DISCHARGE</sub>	Discharge time	Maximum time discharge current is applied		1		sec
IDISCHARGE	Discharge current			8		mA
I <sub>FAULT</sub>	Fault current after a time-out fault			2		mA
V <sub>WAKE</sub>	Wake threshold (with respect to $V_{\text{REG}}$ )	Voltage on VFB to detect battery absent during wake		50		mV
V <sub>DISCH</sub>	Discharge threshold	Voltage on VFB to detect battery absent during discharge		1.55		V
PWM HIGH-SIDE	DRIVER (HIDRV)					
R <sub>DS_HI_ON</sub>	High-side driver (HSD) turnon resistance	$V_{BTST} - V_{PH} = 5.5 V$		3.3	6	Ω
R <sub>DS_HI_OFF</sub>	High-side driver turnoff resistance	$V_{BTST} - V_{PH} = 5.5 V$		1	1.3	Ω
V <sub>BTST_REFRESH</sub>	Bootstrap refresh comparator threshold voltage	$V_{\text{BTST}} - V_{\text{PH}}$ when low-side refresh pulse is requested	4	4.2		V
PWM LOW-SIDE	DRIVER (LODRV)				·	
R <sub>DS_LO_ON</sub>	Low side driver (LSD) turnon resistance			4.1	7	Ω
R <sub>DS_LO_OFF</sub>	Low side driver turnoff resistance			1	1.4	Ω
PWM DRIVER TI	MING				·	
	Driver dead time	Dead time when switching between LSD and HSD, no load at LSD and HSD		30		ns
PWM OSCILLAT	OR					
V <sub>RAMP_HEIGHT</sub>	PWM ramp height	As percentage of VCC		7		%
	PWM switching frequency		510	600	690	kHz
INTERNAL SOFT	Γ START (8 steps to regulation current IC⊦	IG)				
	Soft start steps			8		step
	Soft start step time			1.6		ms
CHARGER SECT	TION POWER-UP SEQUENCING					
	Charge-enable delay after power up	Delay from CE = 1 until charger is allowed to turn on		1.5		S
LOGIC IO PIN CI	HARACTERISTICS (CE, STAT1, STAT2, PG	)				
V <sub>IN_LO</sub>	CE input low-threshold voltage				0.8	V
V <sub>IN_HI</sub>	CE input high-threshold voltage		2.1			
V <sub>BIAS_CE</sub>	CE input bias current	V = 3.3 V (CE has internal 1-M $\Omega$ pulldown resistor)			6	μA
V <sub>OUT_LO</sub>	STAT1, STAT2, PG output low saturation voltage	Sink current = 5 mA			0.5	V
I <sub>OUT_HI</sub>	Leakage current	V = 32 V			1.2	μA

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### **TYPICAL CHARACTERISTICS**

#### Table 1. Table of Graphs

	Figure
VREF, REGN, and $\overline{PG}$ Power Up (CE = 1)	Figure 2
Charge Enable	Figure 3
Current Soft-Start (CE = 1)	Figure 4
Charge Disable	Figure 5
Continuous-Conduction Mode-Switching Waveforms	Figure 6
Cycle-by-Cycle Synchronous to Nonsynchronous	Figure 7
Transient System Load (DPM)	Figure 8
Battery Insertion	Figure 9
Batter- to-Ground Short Protection	Figure 10
Battery-to-Ground Short Transition	Figure 11
Efficiency vs Output Current	Figure 12

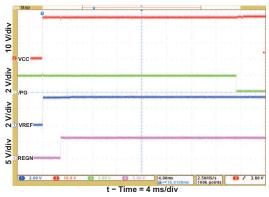
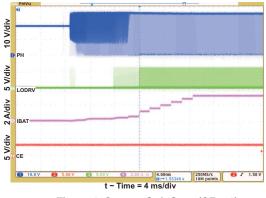


Figure 2. VREF, REGN, and  $\overline{PG}$  Power Up (CE = 1)





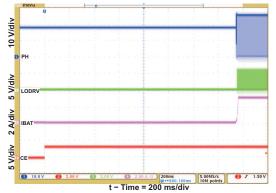


Figure 3. Charge Enable

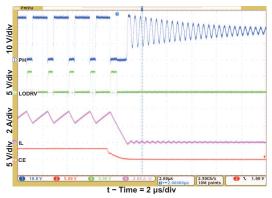


Figure 5. Charge Disable



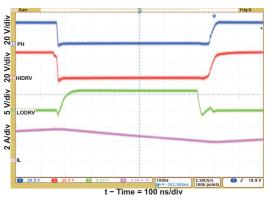


Figure 6. Continuous-Conduction Mode-Switching Waveform

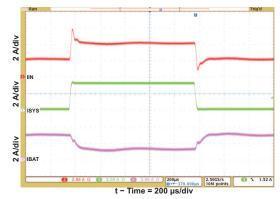


Figure 8. Transient System Load (DPM)

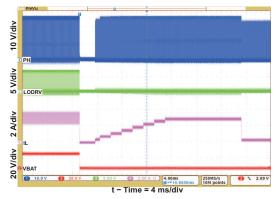
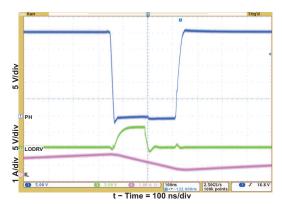


Figure 10. Battery-to-GND Short Protection



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Figure 7. Cycle-by-Cycle Synchronous to Nonsynchronous

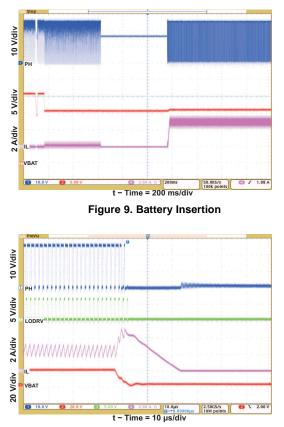
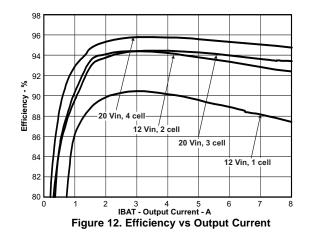


Figure 11. Battery-to-GND Short Transition



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**EXAS** 

STRUMENTS

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### Pin Functions – 24-Pin QFN

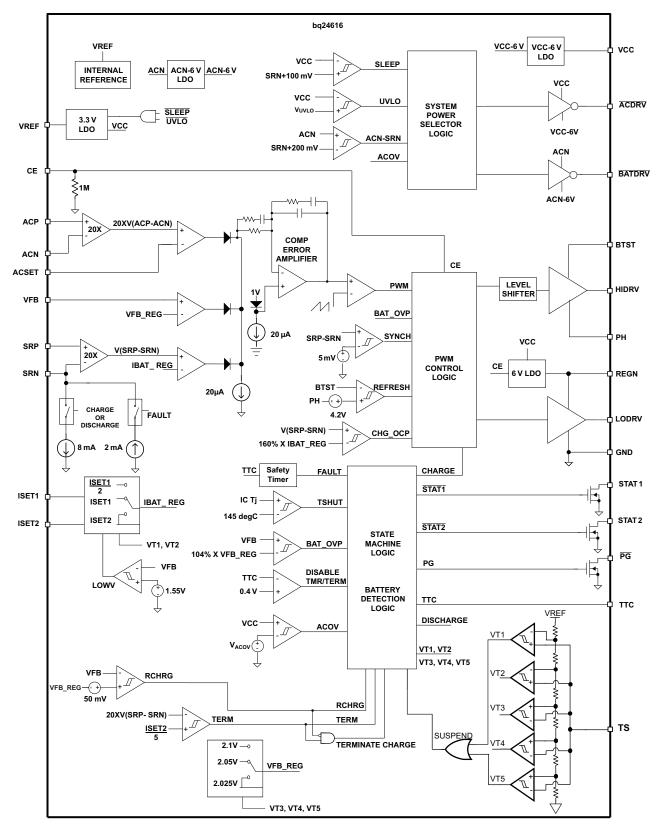
	PIN		FUNCTION DESCRIPTION
NO.	NAME	I/O	
1	ACN	Ι	Adapter current-sense resistor, negative input. A 0.1-µF ceramic capacitor is placed from ACN to ACP to provide differential-mode filtering. An optional 0.1-µF ceramic capacitor is placed from the ACN pin to GND for common-mode filtering.
2	ACP	Ι	Adapter current-sense resistor, positive input. A 0.1-µF ceramic capacitor is placed from ACN to ACP to provide differential-mode filtering. A 0.1-µF ceramic capacitor is placed from the ACP pin to GND for common-mode filtering.
3	ACDRV	0	AC adapter to system MOSFET driver output. Connect through a 1-k $\Omega$ resistor to the gate of the ACFET P-channel power MOSFET and the reverse-conduction-blocking P-channel power MOSFET. The internal gate drive is asymmetrical, allowing a quick turnoff and slow turnon, in addition to the internal break-before-make logic with respect to BATDRV. If needed, an optional capacitor from gate to source of the ACFET is used to slow down the ON and OFF times.
4	CE	Ι	Charge-enable active-HIGH logic input. HI enables charge. LO disables charge. It has an internal 1-MΩ pulldown resistor.
5	STAT1	0	Open-drain charge-status pin to indicate various charger operations (See Table 3)
6	TS	Ι	Temperature qualification voltage input for battery-pack negative-temperature-coefficient thermistor. Program the hot and cold temperature window with a resistor divider from VREF to TS to GND. (See Figure 17)
7	ттс	Ι	Fast-charge safety timer and termination control. Connect a capacitor from this node to GND to set the timer. When this input is LOW, the fast-charge timer and termination are disabled. When this input is HIGH, the fast-charge timer is disabled, but termination is allowed.
8	PG	0	Open-drain power-good status output. Active-LOW when IC has a valid VCC (not in UVLO or ACOV or SLEEP mode). Active-HIGH when IC has an invalid VCC. PG can be used to drive an LED or communicate with a host processor.
9	STAT2	0	Open-drain charge-status pin to indicate various charger operations (See Table 3)
10	VREF	0	3.3-V regulated voltage output. Place a 1-μF ceramic capacitor from VREF to GND pin close to the IC. This voltage could be used for programming of voltage and current regulation and for programming the TS threshold.
11	ISET1	Ι	Fast-charge current-set input. The voltage on the ISET1 pin programs the fast-charge current-regulation set-point. To avoid early termination during the $V_{T1}$ and $V_{T2}$ range, fast-charge current must be higher than 2 times the termination current.
12	VFB	Ι	Output-voltage analog-feedback adjustment. Connect the output of a resistive voltage divider from the battery terminals to this node to adjust the output battery-regulation voltage.
13	SRN	I/O	Charge current-sense resistor, negative input. A 0.1-µF ceramic capacitor is placed from SRN to SRP to provide differential-mode filtering. An optional 0.1-µF ceramic capacitor is placed from the SRN pin to GND for common-mode filtering.
14	SRP	I/O	Charge current-sense resistor, positive input. A 0.1-µF ceramic capacitor is placed from SRN to SRP to provide differential-mode filtering. A 0.1-µF ceramic capacitor is placed from the SRP pin to GND for common-mode filtering.
15	ISET2	Ι	Pre-charge and termination current-set input. The voltage of ISET2 pin programs the pre-charge current-regulation set-point and termination-current trigger point.
16	ACSET	Ι	Adapter current-set input. The voltage on the ACSET pin programs the input current-regulation set-point during dynamic power management (DPM)
17	GND		Low-current sensitive analog/digital ground. On PCB layout, connect with thermal underneath the IC.
18	REGN	0	PWM low-side driver positive 6-V supply output. Connect a 1-µF ceramic capacitor from REGN to the GND pin, close to the IC. Use for low-side driver and high-side driver bootstrap voltage by connecting a small-signal Schottky diode from REGN to BTST.
19	LODRV	0	PWM low-side driver output. Connect to the gate of the low-side power MOSFET with a short trace.
20	PH	Ι	PWM high-side driver negative supply. Connect to the phase-switching node (junction of the low-side power MOSFET drain, high-side power MOSFET source, and output inductor).
21	HIDRV	0	PWM high-side driver output. Connect to the gate of the high-side power MOSFET with a short trace.
22	BTST	Ι	PWM high-side driver positive supply. Connect the 0.1-µF bootstrap capacitor from PH to BTST, and a bootstrap Schottky diode from REGN to BTST.
23	BATDRV	0	Battery to system MOSFET driver output. Gate drive for the battery to system load BAT PMOS power FET to isolate the system from the battery to prevent current flow from the system to the battery, while allowing a low-impedance path from battery to system. Connect this pin through a 1-k $\Omega$ resistor to the gate of the input BAT P-channel MOSFET. Connect the source of the FET to the system load-voltage node. Connect the drain of the FET to the battery-pack positive terminal. The internal gate drive is asymmetrical to allow a quick turnoff and slow turnon, in addition to the internal break-before-make logic with respect to ACDRV. If needed, an optional capacitor from gate to source of the BATFET is used to slow down the ON and OFF times.
24	VCC	Ι	IC power positive supply. Connect through a $10-\Omega$ resistor to the common-source (diode-OR) point: source of high-side P-channel MOSFET and source of reverse-blocking power P-channel MOSFET. Place a $1-\mu$ F ceramic capacitor from VCC to GND pin close to the IC.
	Thermal pad		Exposed pad beneath the IC. Always solder the thermal pad to the board, and have vias on the thermal pad plane star-connecting to GND and to the ground plane for a high-current power converter. It also serves as a thermal pad to dissipate the heat.

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### **BLOCK DIAGRAM**

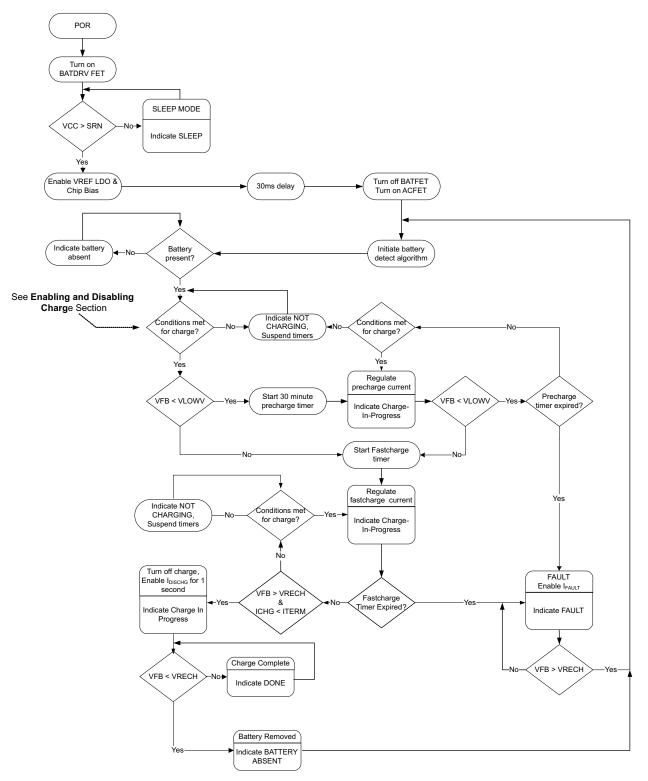






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#### **OPERATIONAL FLOWCHART**

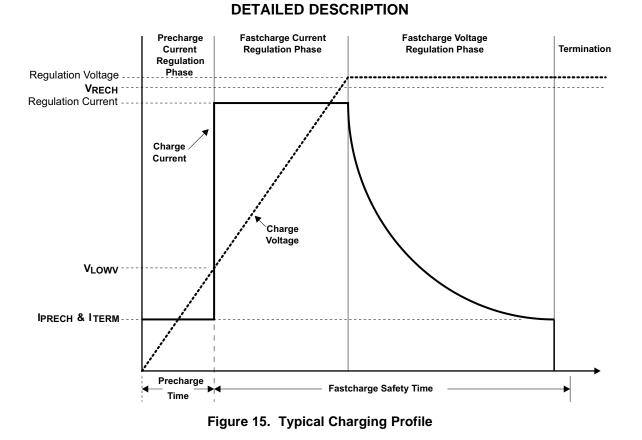




**ISTRUMENTS** 

FXAS

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# Battery Voltage Regulation

The bq24616 uses a high-accuracy voltage band gap and regulator for high charging-voltage accuracy. The charge voltage is programmed via a resistor divider from the battery to ground, with the midpoint tied to the VFB pin. The voltage at the VFB pin is regulated to 2.1 V in the 0°C–45°C range, giving the following equation for the regulation voltage:

$$V_{\text{BAT}} = 2.1 \text{ V } \times \left[1 + \frac{\text{R2}}{\text{R1}}\right], \tag{1}$$

where R2 is connected from VFB to the battery and R1 is connected from VFB to GND.

#### **Battery Current Regulation**

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The ISET1 input sets the maximum fast-charging current in the 10°C–60°C range. Battery-charge current is sensed by resistor  $R_{SR}$ , connected between SRP and SRN. The full-scale differential voltage between SRP and SRN is 100 mV. Thus, for a 10-m $\Omega$  sense resistor, the maximum charging current is 10 A. The equation for charge current is:

$$I_{CHARGE} = \frac{V_{ISET1}}{20 \times R_{SR}}$$
(2)

 $V_{\text{ISET1}}$ , the input voltage range of ISET1, is between 0 V and 2 V. The SRP and SRN pins are used to sense voltage across  $R_{\text{SR}}$  with default value of 10 m $\Omega$ ; however, resistors of other values can also be used. A larger sense resistor gives a larger sense voltage and a higher regulation accuracy, but at the expense of higher conduction loss.



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#### Input Adapter Current Regulation

The total input from an ac adapter or other dc source is a function of the system supply current and the battery charging current. System current normally fluctuates as portions of the systems are powered up or down. Without dynamic power management (DPM), the source must be able to supply the maximum system current and the maximum charger input current simultaneously. By using DPM, the battery charger reduces the charging current when the input current exceeds the input current limit set by ACSET. The current capability of the ac adaptor can be lowered, reducing system cost.

Similar to setting battery regulation current, adaptor current is sensed by resistor R<sub>AC</sub> connected between ACP and ACN. Its maximum value is set by ACSET using Equation 3:

$$I_{\text{DPM}} = \frac{V_{\text{ACSET}}}{20 \times R_{\text{AC}}}$$
(3)

V<sub>ACSET</sub>, the input voltage range of ACSET, is between 0 and 2 V. The ACP and ACN pins are used to sense voltage across R<sub>AC</sub> with a default value of 10 mΩ; however, resistors of other values can also be used. A larger sense resistor gives a larger sense voltage and a higher regulation accuracy, but at the expense of higher conduction loss.

#### Precharge

On power up, if the battery voltage is below the V<sub>LOWV</sub> threshold, the bq24616 applies the precharge current to the battery. This feature is intended to revive deeply discharged cells. If the VLOWV threshold is not reached within 30 minutes of initiating precharge, the charger turns off and a FAULT is indicated on the status pins.

The precharge current (I<sub>PRECHARGE</sub>) is determined by the voltage on the ISET2 pin (V<sub>ISET2</sub>) according to Equation 4.

$$I_{\text{PRECHARGE}} = \frac{V_{\text{ISET2}}}{100 \times R_{\text{SR}}}$$

#### Charge Termination, Recharge, and Safety Timer

The bq24616 monitors the charging current during the voltage regulation phase. When V<sub>TTC</sub> is valid, termination is detected while the voltage on the VFB pin is higher than the V<sub>RECH</sub> threshold AND the charge current is less than the I<sub>TERM</sub> threshold, as calculated in Equation 5:

$$I_{\text{TERM}} = \frac{V_{\text{ISET2}}}{100 \times R_{\text{SR}}}$$
(5)

VISET2, the input voltage of ISET2, is between 0 and 2 V. The minimum precharge/termination current is clamped to be around 125 mA with default 10-m $\Omega$  sensing resistor. As a safety backup, the bq24616 also provides a programmable charge timer. The charge time is programmed by the capacitor connected between the TTC pin and GND, and is given by Equation 6

$$t_{CHARGE} = C_{TTC} \times K_{TTC}$$

where  $C_{TTC}$  (range from 0.01 µF to 0.11 µF to give 1-h to 10-h safety time) is the capacitor connected from the TTC pin to GND, and  $K_{TTC}$  is the constant multiplier (5.6 min/nF).

A new charge cycle is initiated and the fast-charge safety timer is reset when one of the following conditions occurs:

- The battery voltage falls below the recharge threshold.
- A power-on-reset (POR) event occurs.
- CE is toggled.

The TTC pin may be taken LOW to disable termination and to disable the safety timer. If TTC is pulled to VREF, the bq24616 continues to allow termination but disables the safety timer. TTC taken low resets the safety timer. When ACOV, VCCLOWV, and SLEEP mode resume normal, the safety timer also is reset.

(4)

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### Power Up

The bq24616 uses a SLEEP comparator to determine the source of power on the VCC pin, because VCC can be supplied either from the battery or the adapter. If the VCC voltage is greater than the SRN voltage, the bq24616 enables the ACFET and disables BATFET. If all other conditions are met for charging, the bq24616 then attempts to charge the battery (see *Enable and Disable Charging Enable and Disable Charging*). If the SRN voltage is greater than VCC, indicating that the battery is the power source, the bq24616 enables BATFET, and enters a low-quiescent-current (<15-µA) SLEEP mode to minimize current drain from the battery.

If VCC is below the UVLO threshold, the device is disabled, ACFET turns of, and BATFET turns on.

### Enable and Disable Charging

The following conditions must be valid before charge is enabled:

- CE is HIGH.
- The device is not in UVCCLOWV mode.
- The device is not in SLEEP mode.
- The VCC voltage is lower than the ac overvoltage threshold (VCC <  $V_{ACOV}$ )
- 30-ms delay is complete after initial power up.
- The REGN LDO and VREF LDO voltages are at the correct levels.
- Thermal shut (TSHUT) is not valid.
- TS fault is not detected.

Any of the following conditions stops on-going charging:

- CE is LOW.
- Adapter is removed, causing the device to enter VCCLOWV or SLEEP mode.
- Adapter is over voltage.
- The REGN or VREF LDOs are overloaded.
- TSHUT IC temperature threshold is reached (145°C on rising edge with 15°C hysteresis).
- TS voltage goes out of range, indicating the battery temperature is too hot or too cold.
- TTC safety timer times out.

#### System Power Selector

The bq24616 automatically switches adapter or battery power to the system load. The battery is connected to the system by default during power up or during SLEEP mode. The battery is disconnected from the system and then the adapter is connected to the system 30 ms after exiting SLEEP. An automatic break-before-make logic prevents shoot-through currents when the selectors switch.

ACDRV is used to drive a pair of back-to-back p-channel power MOSFETs between the adapter and ACP with sources connected together and to VCC. The FET connected to the adapter prevents reverse discharge from the battery to the adapter when turned off. The p-channel FET with the drain connected to the adapter input provides reverse battery discharge protection when off, and also minimizes system power dissipation with its low r<sub>DS(on)</sub> compared to a Schottky diode. The other p-channel FET connected to ACP separates the battery from the adapter, and provides a limited dl/dt when connecting the adapter to the system by controlling the FET turnon time. The BATDRV controls a p-channel power MOSFET placed between BAT and the system.

When the adapter is not detected, ACDRV is pulled to VCC to keep ACFET off, disconnecting the adapter from the system. BATDRV stays at ACN-6V to connect the battery to the system.

Approximately 30 ms after the device comes out of SLEEP mode, the system begins to switch from battery to adapter. The break-before-make logic keeps both ACFET and BATFET off for 10 µs before ACFET turns on. This prevents shoot-through current or any large discharging current from going into the battery. BATDRV is pulled up to ACN and the ACDRV pin is set to VCC-6V by an internal regulator to turn on p-channel ACFET, connecting the adapter to the system.

When the adapter is removed, the system waits until VCC drops back to within 200 mV above SRN to switch from the adapter back to the battery. The break-before-make logic still keeps 10-µs dead time. The ACDRV is pulled up to VCC and the BATDRV pin is set to ACN-6V by an internal regulator to turn on p-channel BATFET, connecting the battery to the system.



Asymmetrical gate drive (fast turnoff and slow turnon) for the ACDRV and BATDRV drivers provides fast turnoff and slow turnon of the ACFET and BATFET to help the break-before-make logic and to allow a soft start at turnon of either FET. The soft-start time can be further increased by putting a capacitor from gate to source of the p-channel power MOSFETs.

#### Automatic Internal Soft-Start Charger Current

The charger automatically soft-starts the charger regulation current every time the charger goes into fast-charge to ensure there is no overshoot or stress on the output capacitors or the power converter. The soft-start consists of stepping up the charge regulation current in eight evenly divided steps up to the programmed charge current. Each step lasts around 1.6 ms, for a typical rise time of 12.8ms. No external components are needed for this function.

#### **Converter Operation**

The synchronous buck PWM converter uses a fixed-frequency voltage mode with a feed-forward control scheme. A type-III compensation network allows using ceramic capacitors at the output of the converter. The compensation input stage is connected internally between the feedback output (FBO) and the error amplifier input (EAI). The feedback compensation stage is connected between the error amplifier input (EAI) and error amplifier output (EAO). The LC output filter is selected to give a resonant frequency of 12 kHz–17 kHz for the bq24616, where the resonant frequency,  $f_o$ , is given by:

$$f_{\rm o} = \frac{1}{2\pi \sqrt{L_{\rm o}C_{\rm o}}} \tag{7}$$

An internal sawtooth ramp is compared to the internal EAO error-control signal to vary the duty cycle of the converter. The ramp height is 7% of the input adapter voltage, making it always directly proportional to the input adapter voltage. This cancels out any loop gain variation due to a change in input voltage and simplifies the loop compensation. The ramp is offset by 300 mV in order to allow zero-percent duty cycle when the EAO signal is below the ramp. The EAO signal is also allowed to exceed the sawtooth ramp signal in order to get a 100% duty-cycle PWM request. Internal gate-drive logic allows achieving 99.5% duty cycle while ensuring the N-channel upper device always has enough voltage to stay fully on. If the BTST pin to PH pin voltage falls below 4.2 V for more than 3 cycles, then the high-side n-channel power MOSFET is turned off and the low-side n-channel power MOSFET is turned on to pull the PH node down and recharge the BTST capacitor. Then the high-side driver returns to 100% duty-cycle operation until the (BTST-PH) voltage is detected to fall low again due to leakage current discharging the BTST capacitor below 4.2 V, and the reset pulse is reissued.

The fixed-frequency oscillator keeps tight control of the switching frequency under all conditions of input voltage, battery voltage, charge current, and temperature, simplifying output filter design and keeping the switching frequency out of the audible noise region. Also see *Application Information* for how to select the inductor, capacitor and MOSFET.

#### Synchronous and Non-Synchronous Operation

The charger operates in synchronous mode when the SRP-SRN voltage is above 5 mV (0.5-A inductor current for a 10-m $\Omega$  sense resistor). During synchronous mode, the internal gate-drive logic ensures there is break-before-make complementary switching to prevent shoot-through currents. During the 30-ns dead time where both FETs are off, the body-diode of the low-side power MOSFET conducts the inductor current. Having the low-side FET turn on keeps the power dissipation low and allows safely charging at high currents. During synchronous mode, the inductor current is always flowing and the converter operates in continuous-conduction mode (CCM), creating a fixed two-pole system.

The charger operates in non-synchronous mode when the SRP-SRN voltage is below 5 mV (0.5-A inductor current for a  $10\text{-m}\Omega$  sense resistor). The charger is forced into non-synchronous mode when the battery voltage is lower than 2 V or when the average SRP-SRN voltage is lower than 1.25 mV.

During non-synchronous operation, the body diode of the lower-side MOSFET can conduct the positive inductor current after the high-side n-channel power MOSFET turns off. When the load current decreases and the inductor current drops to zero, the body diode is naturally turned off and the inductor current becomes discontinuous. This mode is called discontinuous-conduction mode (DCM). During DCM, the low-side n-channel power MOSFET turns on for around 80 ns when the bootstrap capacitor voltage drops below 4.2 V; then the low-side power MOSFET turns off and stays off until the beginning of the next cycle, where the high-side power

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MOSFET is turned on again. The 80-ns low-side MOSFET on-time is required to ensure the bootstrap capacitor is always recharged and able to keep the high-side power MOSFET on during the next cycle. This is important for battery chargers, where unlike regular dc-dc converters, there is a battery load that maintains a voltage and can both source and sink current. The 80-ns low-side pulse pulse the PH node (connection between high- and low-side MOSFETs) down, allowing the bootstrap capacitor to recharge up to the REGN LDO value. After 80-ns, the low-side MOSFET is kept off to prevent negative inductor current from occurring.

At very low currents during non-synchronous operation, there may be a small amount of negative inductor current during the 80-ns recharge pulse. The charge should be low enough to be absorbed by the input capacitance. Whenever the converter goes into zero percent duty-cycle, the high-side MOSFET does not turn on, and the low-side MOSFET does not turn on (only 80-ns recharge pulse) either, and there is almost no discharge from the battery.

During the DCM mode, the loop response automatically changes and has a single-pole system at which the pole is proportional to the load current, because the converter does not sink current, and only the load provides a current sink. This means at very low currents the loop response is slower, as there is less sinking current available to discharge the output voltage.

#### Cycle-by-Cycle Charge Undercurrent Protection

If the SRP-SRN voltage decreases below 5 mV (the charger is also forced into non-synchronous mode when the average SRP-SRN voltage is lower than 1.25 mV), the low-side FET is turned off for the remainder of the switching cycle to prevent negative inductor current. During DCM, the low-side FET only turns on for at around 80 ns to provide refresh charge for the bootstrap capacitor when the bootstrap capacitor voltage drops below 4.2 V. This is important to prevent negative inductor current from causing a boost effect in which the input voltage increases as power is transferred from the battery to the input capacitors and leads to an overvoltage stress on the VCC node and potentially causes damage to the system.

#### Input Overvoltage Protection (ACOV)

ACOV provides protection to prevent system damage due to high input voltage. Once the adapter voltage reaches the ACOV threshold, charge is disabled and the system is switched to the battery instead of the adapter.

#### Input Undervoltage Lockout (UVLO)

The system must have a minimum VCC voltage to allow proper operation. This VCC voltage could come from either the input adapter or the battery, because a conduction path exists from the battery to VCC through the high-side NMOS body diode. When VCC is below the UVLO threshold, all circuits on the IC are disabled, and the gate-drive bias to ACFET and BATFET is disabled. ACFET is OFF and BATFET is ON.

#### **Battery Overvoltage Protection**

The converter does not allow the high-side FET to turn on until the BAT voltage goes below 102% of the regulation voltage. This allows one-cycle response to an overvoltage condition, such as occurs when the load is removed or the battery is disconnected. An 8-mA current sink from SRP/SRN to GND is on only during charge and allows discharging the stored output inductor energy that is transferred to the output capacitors. BATOVP also suspends the safety timer.

#### Cycle-by-Cycle Charge Overcurrent Protection

The charger has secondary cycle-to-cycle overcurrent protection. It monitors the charge current, and prevents the current from exceeding 160% of the programmed charge current. The high-side gate drive turns off when the overcurrent is detected, and automatically resumes when the current falls below the overcurrent threshold.

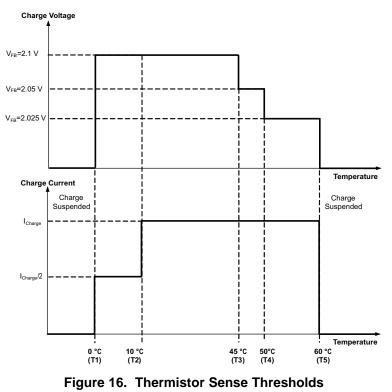
#### **Thermal Shutdown Protection**

The QFN package has low thermal impedance, which provides good thermal conduction from the silicon to the ambient, to keep junctions temperatures low. As an added level of protection, the charger converter turns off and self-protects whenever the junction temperature exceeds the TSHUT threshold of 145°C. The charger stays off until the junction temperature falls below 130°C, then the charger soft-starts again if all other enable charge conditions are valid. Thermal shutdown also suspends the safety timer.



#### **Temperature Qualification and JEITA Guideline**

The controller continuously monitors battery temperature by measuring the voltage between the TS pin and GND. A negative-temperature-coefficient (NTC) thermistor and an external voltage divider typically develop this voltage. The controller compares this voltage against its internal thresholds to determine if charging is allowed. To initiate a charge cycle, the voltage on the TS pin must be within the V<sub>T1</sub> to V<sub>T5</sub> thresholds. If V<sub>TS</sub> is outside of this range, the controller suspends charge and waits until the battery temperature is within the V<sub>T1</sub> to V<sub>T5</sub> range. During the charge cycle, the battery temperature must be within the V<sub>T1</sub> to V<sub>T5</sub> thresholds. If battery temperature is outside of this range, the controller suspends charge and waits until the battery temperature is within the V<sub>T1</sub> to V<sub>T5</sub> range. The controller suspends charge by turning off the PWM charge FETs. If V<sub>TS</sub> is within the range of V<sub>T1</sub> and V<sub>T2</sub>, charge voltage regulation on V<sub>FB</sub> pin is 2.1 V and the charge current is reduced to I<sub>CHARGE</sub>/2 (to avoid early termination during V<sub>T1</sub> and V<sub>T2</sub> range, fast-charge current must be higher than 2 times the termination current); if V<sub>TS</sub> is within the range of V<sub>T2</sub> and V<sub>T3</sub>, the charge voltage regulation on V<sub>FB</sub> pin is 2.1 V; if V<sub>TS</sub> is within V<sub>T4</sub> and V<sub>T5</sub>, the charge voltage regulation on the V<sub>FB</sub> pin is further reduced to 2.025 V; and if V<sub>TS</sub> is within V<sub>T4</sub> and V<sub>T5</sub>, the charge voltage regulation on the V<sub>FB</sub> pin is further reduced to 2.025 V. Figure 16 summarizes the operation. See the "Li-ion battery-charger solutions for JEITA compliance" journal article (SLYT365).



Assuming a 103AT NTC thermistor on the battery pack as shown in Figure 1, the values of RT1 and RT2 can be determined by using the following equations:

$$RT2 = \frac{V_{VREF} \times RTH_{COLD} \times RTH_{HOT} \times \left(\frac{1}{VT1} - \frac{1}{VT5}\right)}{RTH_{HOT} \times \left(\frac{V_{VREF}}{VT5} - 1\right) - RTH_{COLD} \times \left(\frac{V_{VREF}}{VT1} - 1\right)}$$
(8)  
$$RT1 = \frac{\frac{V_{VREF}}{VT1} - 1}{\frac{1}{RT2} + \frac{1}{RTH_{COLD}}}$$
(9)



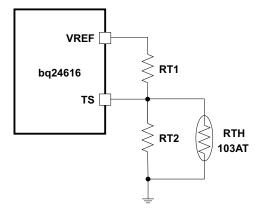


Figure 17. TS Resistor Network

For example, 103AT NTC thermistors are used to monitor the battery pack temperature. Selecting T1 = 0°C for COLD and T5 = 60°C for HOT resuts in  $R_{T2}$  = 6.8 k $\Omega$  and  $R_{T1}$  = 2.2 k $\Omega$  as calculated in the *bq246xx Calculation Tool*, available in the *Tools* & *Software* section of the product folder. A small RC filter is suggested to use for system-level ESD protection.

#### Timer Fault Recovery

The bq24616 provides a recovery method to deal with timer fault conditions. The following summarizes this method:

**Condition 1:** The battery voltage is above the recharge threshold and a time-out fault occurs.

**Recovery Method:** The timer fault clears when the battery voltage falls below the recharge threshold, and battery detection begins. A POR condition or taking CE low also clears the fault.

**Condition 2:** The battery voltage is below the recharge threshold and a time-out fault occurs.

**Recovery Method:** Under this scenario, the bq24616 applies the  $I_{FAULT}$  current to the battery. This small current is used to detect a battery-removal condition and remains on as long as the battery voltage stays below the recharge threshold. If the battery voltage goes above the recharge threshold, the bq24616 disables the fault current and executes the recovery method described in Condition 1. A POR condition or taking CE low also clears the fault.

### PG Output

The open drain  $\overline{PG}$  (power-good) output indicates whether the VCC voltage is valid or not. The open-drain FET turns on whenever bq24616 has a valid VCC input (not in UVLO or ACOV or SLEEP mode). The PG pin can be used to drive an LED or communicate to the host processor.

### CE (Charge Enable)

The CE digital input is used to disable or enable the charge process. A high-level signal on this pin enables charge, provided all the other conditions for charge are met (see *Enable and Disable Charging*). A high-to-low transition on this pin also resets all timers and fault conditions. There is an internal 1-M $\Omega$  pulldown resistor on the CE pin, so if CE is floated, the charge does not turn on.

### Inductor, Capacitor, and Sense Resistor Selection Guidelines

The bq24616 provides internal loop compensation. With this scheme, best stability occurs when the LC resonant frequency,  $f_0$ , is approximately 12 kHz to 17 kHz for the bq24616.

The following table provides a summary of typical LC components for various charge currents:



# Table 2. Typical Inductor, Capacitor, and Sense Resistor Values as a Function of Charge Current forbq24616 (600 kHz Switching Frequency)

CHARGE CURRENT	2A	4A	6A	8A	10A
Output inductor L <sub>O</sub>	6.8 µH	6.8 µH	4.7 µH	3.3 µH	3.3 µH
Output capacitor C <sub>O</sub>	20 µF	20 µF	30 µF	40 µF	40 µF
Sense resistor	10 mΩ				

#### **Charge Status Outputs**

The open-drain STAT1 and STAT2 outputs indicate various charger operations as shown in the Table 3. These status pins can be used to drive LEDs or communicate with the host processor. Note that OFF indicates that the open-drain transistor is turned off.

CHARGE STATE	STAT1	STAT2
Charge in progress	ON	OFF
Charge complete	OFF	ON
Charge suspend, timer fault, AC over-voltage, sleep mode, battery absent	OFF	OFF

# Battery Detection

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For applications with removable battery packs, the bq24616 provides a battery-absent detection scheme to detect insertion or removal of battery packs reliably.

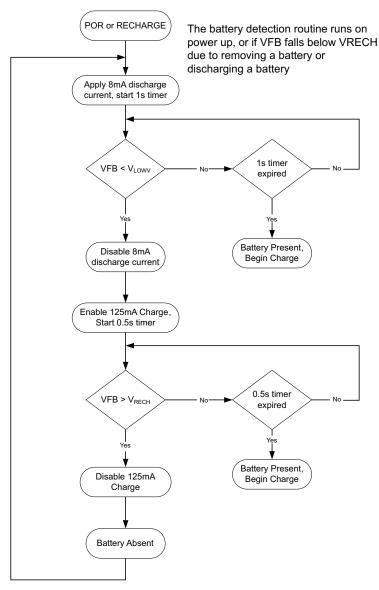


Figure 18. Battery Detection Flowchart

Once the device has powered up, an 8-mA discharge current is applied to the SRN terminal. If the battery voltage falls below the LOWV threshold within 1 second, the discharge source is turned off, and the charger is turned on at low charge current (125 mA). If the battery voltage goes above the recharge threshold within 500 ms, there is no battery present and the cycle restarts. If either the 500-ms or 1-second timer times out before its respective threshold is hit, a battery is detected and a charge cycle is initiated.

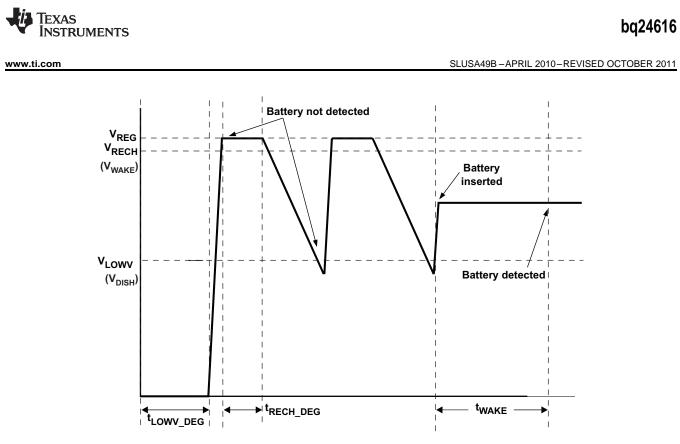


Figure 19. Battery-Detect Timing Diagram

Care must be taken that the total output capacitance at the battery node is not so large that the discharge current source cannot pull the voltage below the LOWV threshold during the 1-second discharge time. The maximum output capacitance can be calculated as follows:

$$C_{MAX} = \frac{I_{DISCH} \times I_{DISCH}}{0.5 \times \left[1 + \frac{R_2}{R_1}\right]}$$
(10)

where  $C_{MAX}$  is the maximum output capacitance,  $I_{DISCH}$  is the discharge current,  $t_{DISCH}$  is the discharge time, and  $R_2$  and  $R_1$  are the voltage feedback resistors from the battery to the VFB pin. The 0.5 factor is the difference between the RECHARGE and the LOWV thresholds at the VFB pin.

#### Example

For a 3-cell Li+ charger, with R2 = 500 k $\Omega$ , R1 = 100  $\Omega$ k (giving 12.6 V for voltage regulation), I<sub>DISCH</sub> = 8 mA, t<sub>DISCH</sub> = 1 second,

$$C_{MAX} = \frac{8mA \times 1sec}{0.5 \times \left[1 + \frac{500k}{100k}\right]} = 2.7 \text{ mF}$$
(11)

Based on these calculations, no more than 2.7 mF should be allowed on the battery node for proper operation of the battery-detection circuit.

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NSTRUMENTS

Texas

### Component List for Typical System Circuit of Figure 1

PART DESIGNATOR	QTY	DESCRIPTION
Q1, Q2, Q3	3	P-channel MOSFET, -30 V, -35 A, PowerPAK 1212-8, Vishay-Siliconix, Si7617DN
Q4, Q5	2	N-channel MOSFET, 30 V, 12 A, PowerPAK 1212-8, Vishay-Siliconix, Sis412DN
D1	1	Diode, dual Schottky, 30 V, 200 mA, SOT23, Fairchild, BAT54C
D2, D3, D4	3	LED diode, green, 2.1V, 20mA, LTST-C190GKT
R <sub>AC</sub> , R <sub>SR</sub>	2	Sense resistor, 10 mΩ, 2010, Vishay-Dale, WSL2010R0100F
L1	1	Inductor, 6.8 μH, 5.5 A, Vishay-Dale IHLP2525CZ
C8, C9, C12, C13	4	Capacitor, ceramic, 10 µF, 35 V, 20%, X7R
C4, C5	2	Capacitor, ceramic, 1 µF, 16 V, 10%, X7R
C1, C3, C6, C11	4	Capacitor, ceramic, 0.1 µF, 16 V, 10%, X7R
C2, C10	2	Capacitor, ceramic, 0.1 µF, 50 V, 10%, X7R
C7	1	Capacitor, ceramic, 1 µF, 50 V, 10%, X7R
C14, C15 (Optional)	2	Capacitor, ceramic, 0.1 µF, 50 V, 10%, X7R
C16	1	Capacitor, ceramic, 2.2 µF, 35 V, 10%, X7R
C <sub>ff</sub>	1	Capacitor, ceramic, 22 pF, 25 V, 10%, X7R
C <sub>TTC</sub>	1	Capacitor, ceramic, 0.056 µF, 16V, 5%, X7R
R1, R3, R5, R7	4	Resistor, chip, 100 kΩ, 1/16W, 0.5%
R2	1	Resistor, chip, 500 kΩ, 1/16W, 0.5%
R4	1	Resistor, chip, 32.4 kΩ, 1/16W, 0.5%
R6	1	Resistor, chip, 10 kΩ, 1/16W, 0.5%
R8	1	Resistor, chip, 22.1 kΩ, 1/16W, 0.5%
R9	1	Resistor, chip, 2.2 kΩ, 1/16W, 1%
R10	1	Resistor, chip, 6.8 kΩ, 1/16W, 1%
R11, R12, R13, R18, R19	5	Resistor, chip, 10 kΩ, 1/16W, 5%
R14, R15 (optional)	2	Resistor, chip, 100 kΩ, 1/16W, 5%
R16	1	Resistor, chip, 100 Ω, 1/16W, 5%
R17	1	Resistor, chip, 10 $\Omega$ , 1/4W, 5%
R20	1	Resistor, chip, 2 Ω, 1W, 5%



### **APPLICATION INFORMATION**

#### **Inductor Selection**

The bq24616 has 600-kHz switching frequency to allow the use of small inductor and capacitor values. Inductor saturation current should be higher than the charging current ( $I_{CHG}$ ) plus half the ripple current ( $I_{RIPPLE}$ ):

$$I_{SAT} \geq I_{CHG} + (1/2) I_{RIPPLE}$$

(12)

The inductor ripple current depends on input voltage ( $V_{IN}$ ), duty cycle (D =  $V_{OUT}/V_{IN}$ ), switching frequency ( $f_S$ ) and inductance (L):

$$I_{\text{RIPPLE}} = \frac{V_{\text{IN}} \times D \times (1 - D)}{f_{\text{S}} \times L}$$
(13)

The maximum inductor ripple current happens with D = 0.5 or close to 0.5. For example, the battery-charging voltage range is from 9 V to 12.6 V for a 3-cell battery pack. For 20-V adapter voltage, 10-V battery voltage gives the maximum inductor ripple current. Another example is a 4-cell battery; the battery-voltage range is from 12 V to 16.8 V, and 12-V battery voltage gives the maximum inductor ripple current.

Usually inductor ripple is designed in the range of 20%–40% of maximum charging current as a trade-off between inductor size and efficiency for a practical design.

The bq24616 has cycle-by-cycle charge undercurrent protection (UCP) by monitoring the charging-current-sensing resistor to prevent negative inductor current. The typical UCP threshold is 5-mV on the falling edge, corresponding to 0.5-A falling edge for a 10-m $\Omega$  charging-current-sensing resistor.

#### **Input Capacitor**

Input capacitor should have enough ripple current rating to absorb the input switching-ripple current. The worst-case rms ripple current is half of the charging current when the duty cycle is 0.5. If the converter does not operate at 50% duty cycle, then the worst-case capacitor rms current  $I_{CIN}$  occurs where the duty cycle is closest to 50% and can be estimated by the following equation:

$$I_{CIN} = I_{CHG} \times \sqrt{D \times (1-D)}$$
<sup>(14)</sup>

A low-ESR ceramic capacitor such as X7R or X5R is preferred for the input decoupling capacitor and should be placed as close as possible to the drain of the high-side MOSFET and source of the low-side MOSFET. The voltage rating of the capacitor must be higher than the normal input-voltage level. A 25-V rating or higher capacitor is preferred for 20-V input voltage. A  $10-\mu$ F to  $20-\mu$ F capacitance is suggested for typical of 3-A to 4-A charging current.

### **Output Capacitor**

The output capacitor also should have enough ripple-current rating to absorb the output switching ripple current. The output-capacitor rms current  $I_{COUT}$  is given:

$$I_{COUT} = \frac{I_{RIPPLE}}{2 \times \sqrt{3}} \approx 0.29 \times I_{RIPPLE}$$
(15)

The output-capacitor voltage ripple can be calculated as follows:

$$\Delta V_{o} = \frac{1}{8LCf_{s}^{2}} \left( V_{BAT} - \frac{V_{BAT}^{2}}{V_{IN}} \right)$$
(16)

At certain input/output voltage and switching frequency, the voltage ripple can be reduced by increasing the output filter LC.

The bq24616 has an internal loop compensator. To get good loop stability, the resonant frequency of the output inductor and output capacitor should be designed between 12 kHz and 17 kHz. The preferred ceramic capacitor is 25-V or higher rating, X7R or X5R, for 4-cell application.

F

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#### Power MOSFET Selection

Two external N-channel MOSFETs are used for a synchronous switching battery charger. The gate drivers are internally integrated into the IC with 6 V of gate-drive voltage. 30-V or higher voltage-rating MOSFETs are preferred for 20-V input voltage, and 40-V or higher rating MOSFETs are perfered for 20-V to 28-V input voltage.

Figure of merit (FOM) is usually used for selecting the proper MOSFET, based on a tradeoff between the conduction loss and switching loss. For a top-side MOSFET, FOM is defined as the product of the MOSFET on-resistance,  $r_{DS(on)}$ , and the gate-to-drain charge,  $Q_{GD}$ . For a bottom-side MOSFET, FOM is defined as the product of the MOSFET on-resistance,  $r_{DS(on)}$ , and the total gate charge,  $Q_{G}$ .

$$OM_{top} = R_{DS(on)} \times Q_{GD}$$
  $FOM_{bottom} = R_{DS(on)} \times Q_{G}$  (17)

The lower the FOM value, the lower the total power loss. Usually lower  $r_{DS(on)}$  has higher cost with the same package size.

The top-side MOSFET loss includes conduction loss and switching loss. It is a function of duty cycle (D =  $V_{OUT}/V_{IN}$ ), charging current (I<sub>CHG</sub>), MOSFET on-resistance  $r_{DS(on)}$ ), input voltage (V<sub>IN</sub>), switching frequency (f<sub>S</sub>), turnon time (t<sub>on</sub>) and turnoff time (t<sub>off</sub>):

$$P_{top} = D \times I_{CHG}^{2} \times R_{DS(on)} + \frac{1}{2} \times V_{IN} \times I_{CHG} \times (t_{on} + t_{off}) \times f_{S}$$
(18)

The first item represents the conduction loss. Usually MOSFET  $r_{DS(on)}$  increases by 50% with a 100°C junction temperature rise. The second term represents the switching loss. The MOSFET turnon and turnoff times are given by:

$$t_{on} = \frac{Q_{SW}}{I_{on}}, t_{off} = \frac{Q_{SW}}{I_{off}}$$
(19)

where  $Q_{sw}$  is the switching charge,  $I_{on}$  is the turnon gate-driving current and  $I_{off}$  is the turnoff gate-driving current. If the switching charge is not given in the MOSFET data sheet, it can be estimated by gate-to-drain charge ( $Q_{GD}$ ) and gate-to-source charge ( $Q_{GS}$ ):

$$Q_{SW} = Q_{GD} + \frac{1}{2} \times Q_{GS}$$
<sup>(20)</sup>

Total gate-driving current can be estimated by the REGN voltage ( $V_{REGN}$ ), MOSFET plateau voltage ( $V_{plt}$ ), total turnon gate resistance ( $R_{on}$ ) and turnoff gate resistance  $R_{off}$ ) of the gate driver:

$$I_{on} = \frac{V_{REGN} - V_{plt}}{R_{on}}, I_{off} = \frac{V_{plt}}{R_{off}}$$
(21)

The conduction loss of the bottom-side MOSFET is calculated with the following equation when it operates in synchronous continuous conduction mode:

$$P_{\text{bottom}} = (1 - D) \times I_{\text{CHG}}^2 \times R_{\text{DS(on)}}$$
(22)

If the SRP-SRN voltage decreases below 5 mV (the charger is also forced into non-synchronous mode when the average SRP-SRN voltage is lower than 1.25 mV), the low-side FET is turned off for the remainder of the switching cycle to prevent negative inductor current.

As a result, all the freewheeling current goes through the body diode of the bottom-side MOSFET. The maximum charging current in non-synchronous mode can be up to 0.9 A (0.5 A typ.) for a 10-m $\Omega$  charging-current-sensing resistor, considering IC tolerance. Choose the bottom-side MOSFET with either an internal Schottky or body diode capable of carrying the maximum non-synchronous mode charging current.

MOSFET gate-driver power loss contributes to the dominant losses in the controller IC when the buck converter is switching. Choosing a MOSFET with a small  $Q_{q total}$  reduces the IC power loss to avoid thermal shutdown.

$$P_{ICLoss\_driver} = V_{IN} \cdot Q_{g\_total} \cdot f_s$$

where  $Q_{q \text{ total}}$  is the total gate charge for both upper and lower MOSFETs at 6-V V<sub>REGN</sub>.

(23)



#### **Input Filter Design**

During adapter hot plug-in, the parasitic inductance and input capacitor from the adapter cable form a second-order system. The voltage spike at the VCC pin may be beyond the IC maximum voltage rating and damage the IC. The input filter must be carefully designed and tested to prevent overvoltage events on the VCC pin. The ACP/ACN pins must be placed after the input ACFET in order to avoid overvoltage stress on these pins during hot plug-in.

There are several methods for damping or limiting the overvoltage spike during adapter hot plug-in. An electrolytic capacitor with high ESR as an input capacitor can damp the overvoltage spike well below the IC maximum pin-voltage rating. A high-current-capability TVS Zener diode can also limit the overvoltage level to an IC-safe level. However, these two solutions may not have low cost or small size.

A cost-effective and small-size solution is shown in Figure 20. R1 and C1 are comprise a damping RC network to damp the hot plug-in oscillation. As a result, the overvoltage spike is limited to a safe level. D1 is used for reverse voltage protection for the VCC pin (it can be the body diode of the input ACFET). C2 is the VCC pin decoupling capacitor and it should be placed as close as possible to the VCC pin. R2 and C2 form a damping RC network to further protect the IC from high-dv/dt and high-voltage spikes. The C2 value should be less than the C1 value so R1 can be dominant over the ESR of C1 to get enough damping effect for hot plug-in. The R1 and R2 packages must be sized to handle the inrush-current power loss according to resistor manufacturer's datasheet. The filter component values always must be verified with the real application, and minor adjustments may be needed to fit in the real application circuit.

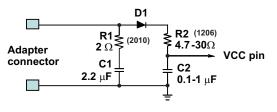


Figure 20. Input Filter

#### PCB Layout

The switching node rise and fall times should be minimized for minimum switching loss. Proper layout of the components to minimize the high-frequency current path loop (see Figure 21) is important to prevent electrical and magnetic field radiation and high-frequency resonant problems. Here is a PCB layout priority list for proper layout. Lay out of the PCB according to this specific order is essential.

- 1. Place the input capacitor as close as possible to the switching MOSFET supply and ground connections, and use the shortest-possible copper trace connection. These parts should be placed on the same layer of PCB, instead of on different layers using vias to make the connection.
- 2. The IC should be placed close to the switching MOSFET gate terminals. Keep the gate-drive signal traces short for a clean MOSFET drive. The IC can be placed on the other side of the PCB of switching MOSFETs.
- 3. Place the inductor input terminal as close as possible to the switching MOSFET output terminal. Minimize the copper area of this trace to lower electrical and magnetic field radiation, but make the trace wide enough to carry the charging current. Do not use multiple layers in parallel for this connection. Minimize parasitic capacitance from this area to any other trace or plane.
- 4. The charging-current-sensing resistor should be placed right next to the inductor output. Route the sense leads connected across the sensing resistor back to the IC in same layer, close to each other (minimize loop area), and do not route the sense leads through a high-current path (see Figure 22 for a Kelvin connection for the best current accuracy). Place decoupling capacitors on these traces next to the IC.
- 5. Place output capacitor next to the sensing resistor output and ground.
- 6. Output-capacitor ground connections must be tied to the same copper that connects to the input capacitor ground before connecting to system ground.

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- 7. Route the analog ground separately from the power ground and use a single ground connection to tie the charger power ground to the charger analog ground. Just beneath the IC, use the copper pour for analog ground, but avoid the power pins to reduce inductive and capacitive noise coupling. Connect the analog ground to GND. Connect the analog ground and power ground together using the thermal pad as the single ground-connection point. Or use a  $0-\Omega$  resistor to tie analog ground to power ground (the thermal pad should tie to analog ground in this case). A star connection under the thermal pad is highly recommended.
- 8. It is critical that the exposed thermal pad on the back side of the IC package be soldered to the PCB ground. Ensure that there are sufficient thermal vias directly under the IC, connecting to the ground plane on the other layers.
- 9. Decoupling capacitors should be placed next to the IC pins. Make trace connections as short as possible.
- 10. All via sizes and numbers should be adequate for a given current path.

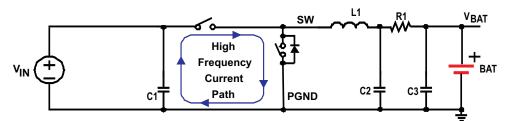


Figure 21. High-Frequency Current Path

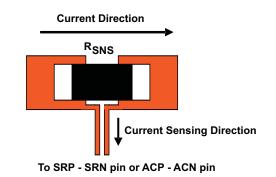


Figure 22. Sensing-Resistor PCB Layout

See the EVM design (SLUU396) for the recommended component placement with trace and via locations. For the QFN information, see SCBA017 and SLUA271.

### **REVISION HISTORY**

C	hanges from Revision A (May 2010) to Revision B	Page
•	Changed descriptions of PH and BTST pins	13
•	Added added text, equations and illustrations from Inductor Selection to PCB Layout	27
•	Corrected equation for caclulating voltage ripple on output capacitor	27



11-Apr-2013

### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	•	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
BQ24616RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	QTJ	Samples
BQ24616RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	QTJ	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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# PACKAGE MATERIALS INFORMATION

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### TAPE AND REEL INFORMATION





### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ24616RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24616RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

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# PACKAGE MATERIALS INFORMATION

26-Jan-2013



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ24616RGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24616RGET	VQFN	RGE	24	250	210.0	185.0	35.0

# **MECHANICAL DATA**



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Quad Flatpack, No-Leads (QFN) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions. F. Falls within JEDEC MO-220.
  - TEXAS INSTRUMENTS www.ti.com

### RGE (S-PVQFN-N24)

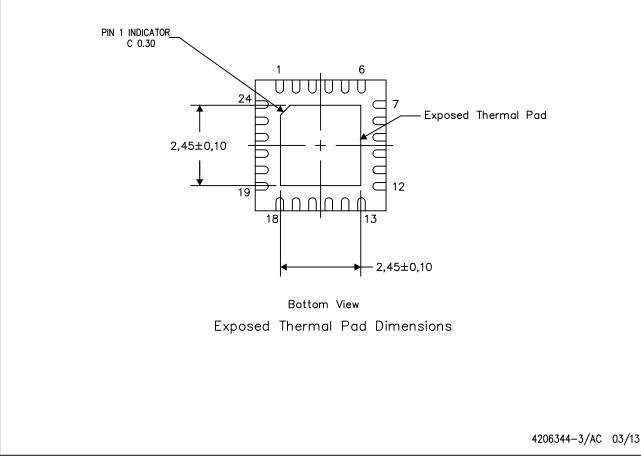
### PLASTIC QUAD FLATPACK NO-LEAD

#### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

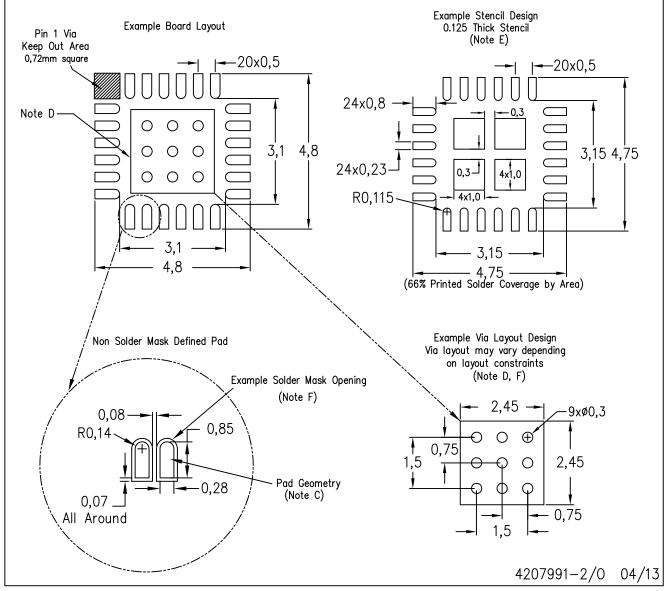


#### NOTES: A. All linear dimensions are in millimeters



# RGE (S-PVQFN-N24)

# PLASTIC QUAD FLATPACK NO-LEAD



NOTES:

- : A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Publication IPC-7351 is recommended for alternate designs.
  - D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <a href="http://www.ti.com">http://www.ti.com</a>.
  - E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
  - F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



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